

<b>Notice of References Cited</b>	Application/Control No. 10/630,683	Applicant(s)/Patent Under Reexamination CHEN, YI-CHEN	
	Examiner Navneet Sonia Khaira	Art Unit 3754	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-5,183,182	02-1993	Comstock et al.	222/129
	B	US-2002/0084288	07-2002	Lewis et al.	222/181.1
	C	US-4,493,440	01-1985	von Buelow et al.	222/109
	D	US-6,209,184	04-2001	Copeland et al.	29/428
	E	US-6,131,773	10-2000	Wade et al.	222/153.02
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.